

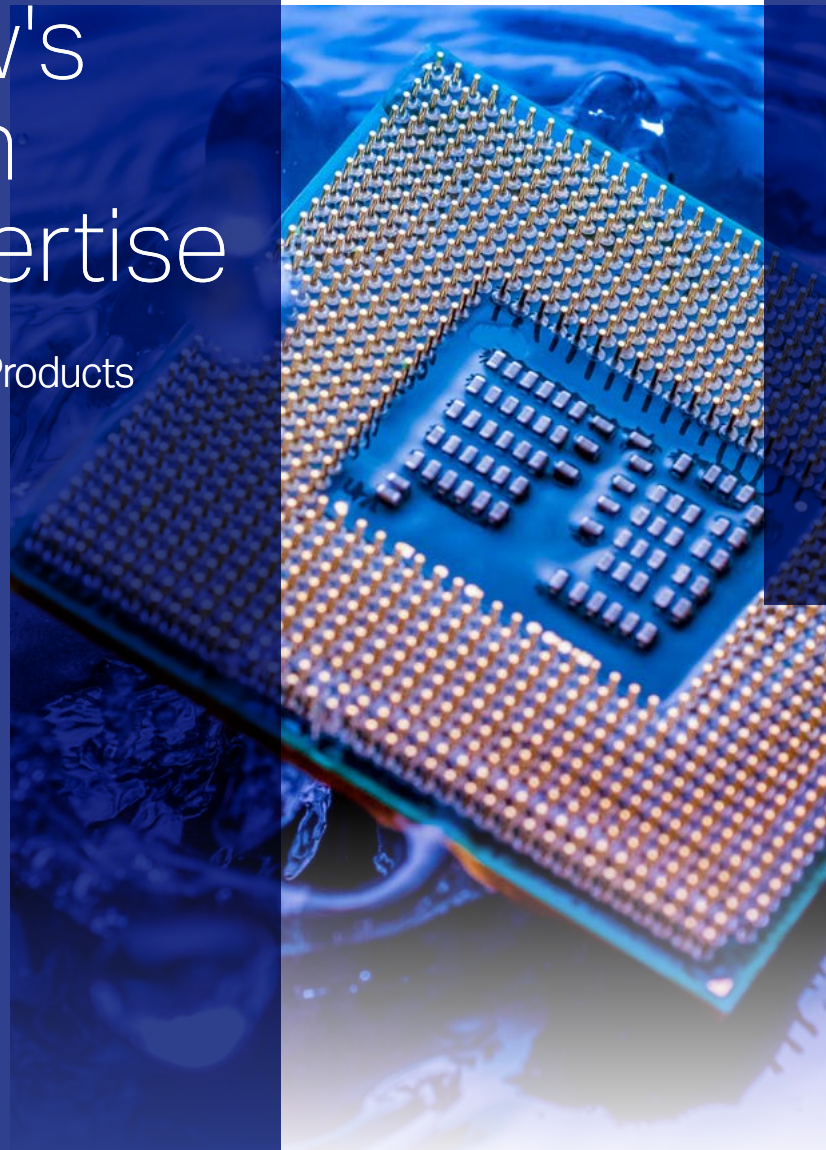
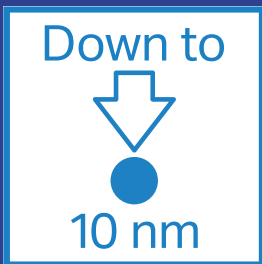


® Knowledge
Beyond
Measure.



Meet Tomorrow's Challenges with Nanoscale Expertise

Particle and Environmental Monitoring Products
for Electronics and Semiconductor



Meet Tomorrow's Challenges with Nanoscale Expertise

Environmental Monitoring Products for Electronics and Semiconductor

Airborne Particle Counters

10 nm to 25 µm measurement

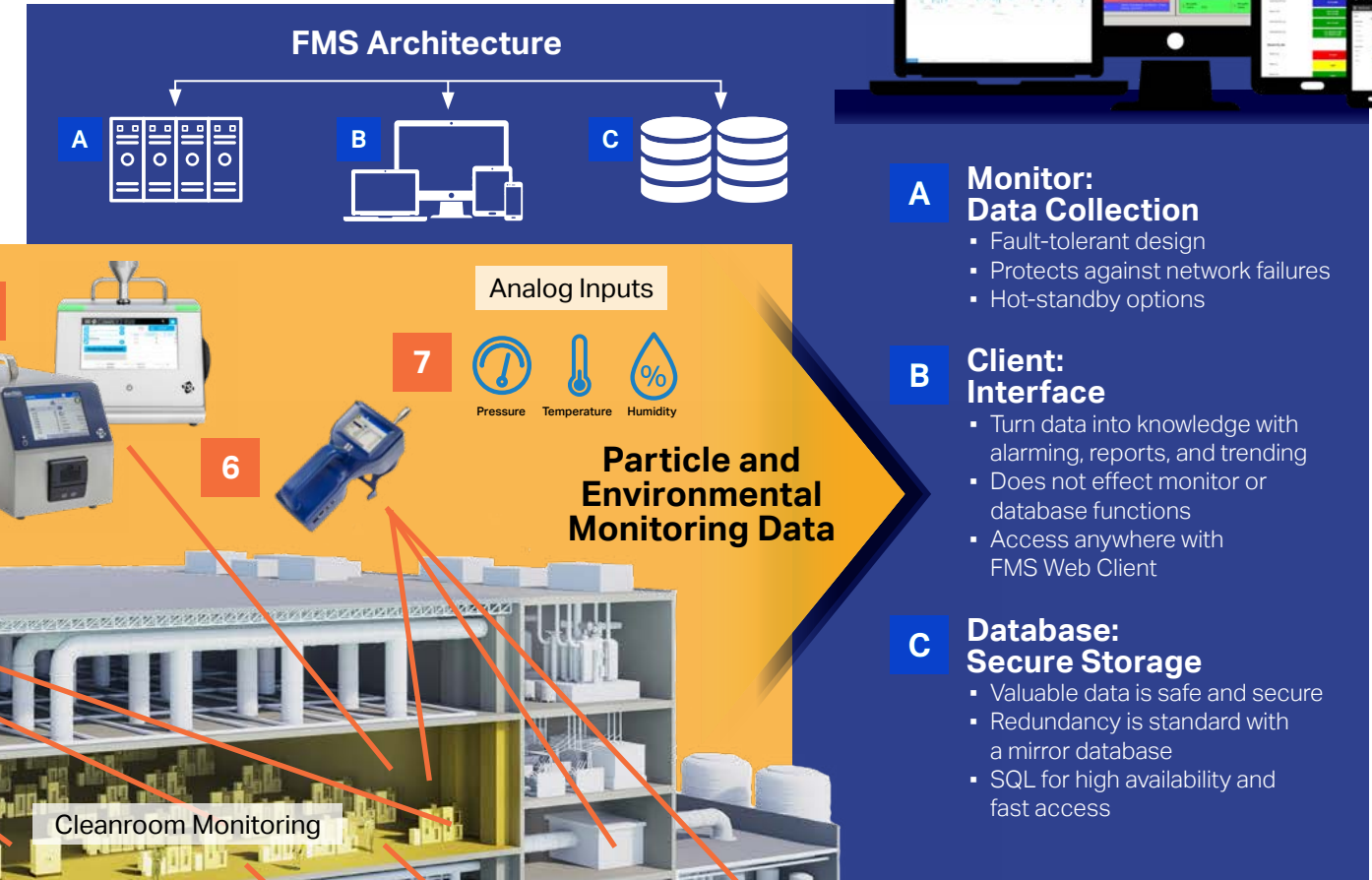
Models for every electronics and semiconductor environment and application including:

- Cleanroom monitoring
- Tool monitoring
- Gas monitoring

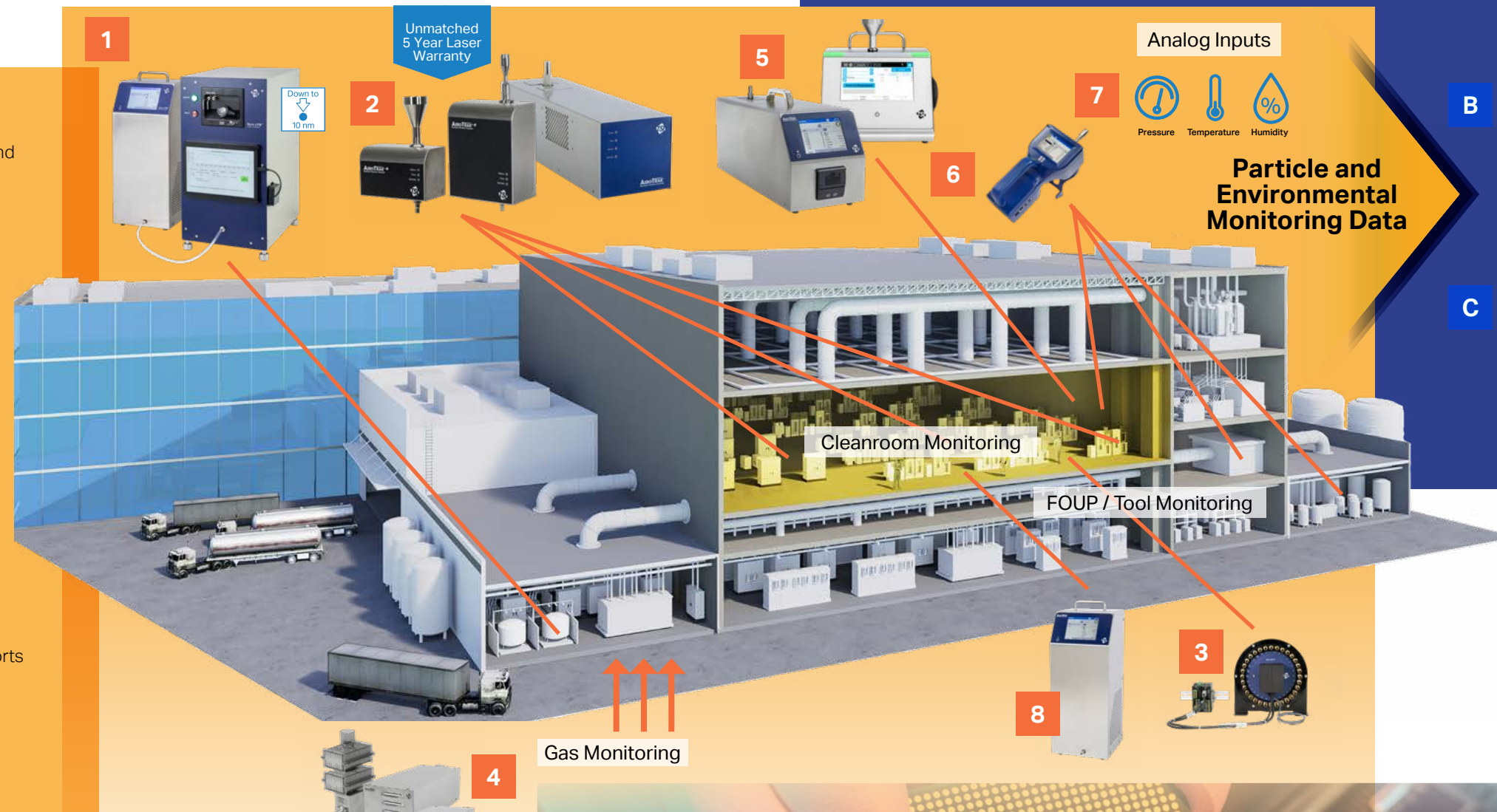
TSI® Facility Monitoring Software: Reliable Monitoring Systems

Distributed. Flexible. Redundant.

- No single point of failure
- Data available where and when you need it
- Easily scalable



- 1 Nano LPM™ System UPW Contamination Monitoring**
 - Reliable 10 nm detection of particulate and dissolved contamination in UPW.
 - Integrated injection port for onsite performance verification
- 2 AeroTrak™ + Remote Particle Counters Ultra-Reliable Data Collection**
 - Protect against network failures with six months of data storage
 - Flexible environmental monitoring system with Wi-Fi® communication
- 3 Aerosol Sampling Manifold**
 - Monitor up to 32 points with a single particle counter
- 4 High Pressure Diffusers**
 - Measure particulate contamination in high-pressure compressed gas systems
- 5 AeroTrak™ + Portable Particle Counters**
 - Different sample modes for monitoring, classifying, and root cause investigation
 - Built-in monitoring and classification reports
- 6 AeroTrak™ Handheld Particle Counters**
- 7 Integrated Environmental Monitoring Probes**
 - Using FMS
- 8 AeroTrak™ Cleanroom Condensation Particle Counter**
 - Confident 24/7 operation
 - Minimal maintenance
 - High flow rates
 - Ultra-low false count rates
 - No contamination or chemicals introduced into the ultra-clean environment



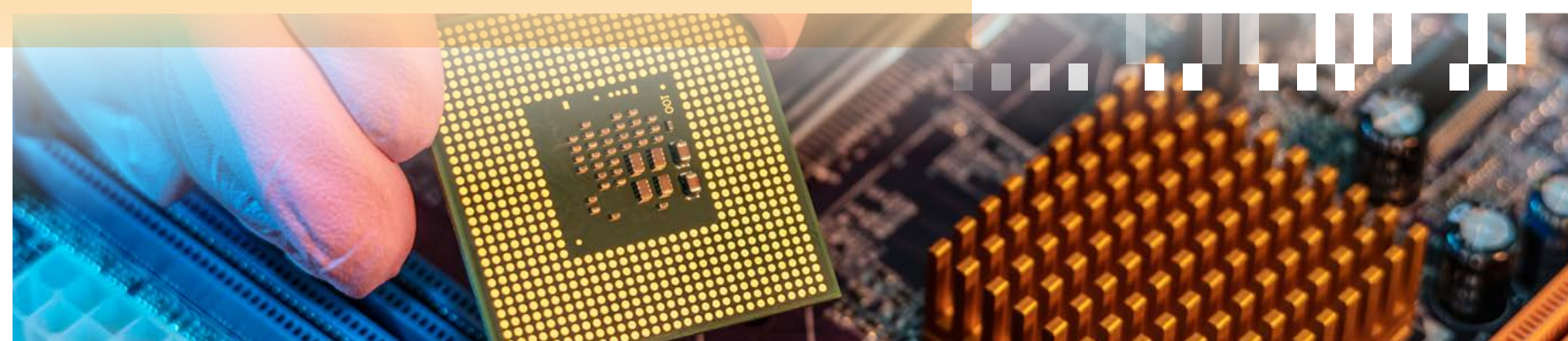
Gas Monitoring

Cleanroom Monitoring

FOUP / Tool Monitoring

Analog Inputs
Pressure Temperature Humidity

Particle and Environmental Monitoring Data



Meet Tomorrow's Challenges with Nanoscale Expertise

Particle and Environmental Monitoring Products for Electronics and Semiconductor

Facility Monitoring System

A reliable monitoring system that supports process control and decreases downtime.

Model	Minimum Particle Size	Benefits and Features
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Remote Particle Counters

Designed for continuous monitoring as part of the Facility Monitoring System with Analog and WiFi options

AeroTrak™+ 6000 series	0.2 µm	0.1 CFM (2.83 LPM) flow rate, includes onboard pump, compact size, many communications options
AeroTrak™+ 7000 series	0.2 µm	0.1 CFM (2.83 LPM) and 1 CFM (28.3 LPM) flow rate, compact size, many communications options
AeroTrak™+ 6310	0.3 µm	1 CFM (28.3 LPM) flow rate, internal pump, 0.3 to 5.0 channels available, field-removable sensor/pump
AeroTrak™ 7110	0.1 µm (100 nm)	1 CFM (28.3 LPM) flow rate, complies with all ISO 21501-4 requirements

Portable Particle Counters

Versatile instruments suitable for classification and monitoring

AeroTrak™+ A100 Series	0.3 µm	1 CFM (28.3 LPM), 1.77 CFM (50 LPM), and 3.53 CFM (100 LPM) flow rate models available, intuitive interface, simplifies sampling with workflows, built-in classification and monitoring reporting capabilities, gas and filter testing
AeroTrak™ 9110	0.1 µm (100 nm)	1 CFM (28.3 LPM) flow rate, includes display and onboard pump, provides classification testing, complies with all ISO 21501-4 requirements

Handheld Particle Counters

Economical choice for higher class cleanrooms and investigations

AeroTrak™ 9303	0.3 µm	0.1 CFM (2.83 LPM) flow rate, 3 channels of simultaneous data, small, lightweight, versatile, low cost
AeroTrak™ 9306	0.3 µm	0.1 CFM (2.83 LPM) flow rate, 6 channels of simultaneous data, versatile

Cleanroom Condensation Particle Counter

The only water-based, laminar flow CPC on the market that can run continuously, 24/7, or as a standalone unit

AeroTrak Cleanroom CPC 9001	0.01 µm (10 nm)	0.1 CFM (2.83 LPM) flow rate, ultralow zero counts for cleanroom processes
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Nanoparticle Monitoring in Ultrapure Water (10 nm)

Empowers data-driven decisions in UPW monitoring...like never before.

Nano LPM™ System	0.01 µm (10 nm)	Detects solid and dissolved contamination >10 nm using nebulization and a specialized cleanroom condensation particle counter.
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Distributed by:

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Knowledge Beyond Measure.

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